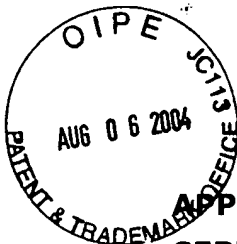


1763
JFW



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT: Yu-Chih Lai

EXAMINER: HASSANZADEH, PARVIZ

SERIAL NO.: 10/092,977

ART UNIT: 1763

FILED: 03/07/2002

ATTY DKT NO.: 67,200-708

TITLED: IN-SITU MEASUREMENT OF WAFER POSITION ON LOWER ELECTRODE

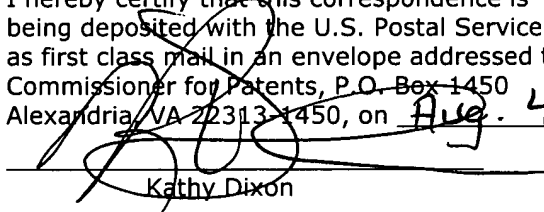
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CERTIFICATE OF MAILING

Please forward all correspondence to:

TUNG & ASSOCIATES
Suite 120
838 W. Long Lake Road
Bloomfield Hills, MI 48302

I hereby certify that this correspondence is
being deposited with the U.S. Postal Service
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Commissioner for Patents, P.O. Box 1450
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Kathy Dixon

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Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENTS, RESPONSE AND REQUEST FOR RECONSIDERATION
UNDER 37 C.F.R. §1.111

Dear Sir:

In response to the Office Action dated May 5, 2004 in the above captioned matter, please enter the following remarks and amendments to the specification and claims: